

## CONTENTS

|   |     |
|---|-----|
| Preface   | v   |
| SPECIALLY INVITED TALK  | 1   |
| Theoretical Studies on Electronic States of Transition<br>Metal Silicides and Transition Metal Disilicides/<br>Silicon Interfaces             | 3   |
| <i>Y. N. Xu, K. M. Zhang, J. H. Xu &amp; X. D. Xie</i>  |     |
| INVITED TALKS   | 17  |
| Surface Analysis by Low Energy Ion Scattering<br>Spectroscopy (ISS)   | 19  |
| <i>T. Hanawa</i>  |     |
| On the Quantitative AES Analysis  | 63  |
| <i>Z. Y. Hua &amp; Q. Wang</i>  |     |
| Depth Resolution of Electron Spectroscopy Analysis  | 76  |
| <i>H. Soezima</i>   |     |
| Current Activities of Surface and Vacuum Science<br>Laboratory, Hokkaido University   | 105 |
| <i>T. Yamashina</i>   |     |
| An Overview of Research Using Thin Film and Surface<br>Analysis Techniques at the Institute of<br>Semiconductors, Chinese Academy of Sciences | 135 |
| <i>C. C. Hsu</i>  |     |
| Angular Resolved and Small Area ESCA<br>Extends Analysis Capabilities   | 153 |
| <i>R. Ohta</i>  |     |
| Electron-Stimulated Desorption  | 169 |
| <i>Y. H. Kuo &amp; F. G. Suen</i>   |     |
| The Adsorption and Desorption on Semiconductor Surfaces   | 192 |
| <i>Y. B. Xu</i>   |     |
| The Electronic Structure and Magnetism of<br>Tungsten Carbide   | 208 |
| <i>Z. D. Lin, C. H. Wang &amp; D. H. Shen</i>   |     |

|  |     |
|--|-----|
| XPS Studies of Cobalt Oxidation and the Thermal Stability of the Oxides<br><i>L. Z. Zhao &amp; V. Y. Young</i>                                   | 217 |
| On Surface Enrichment of a Zn-Cu Alloy<br><i>Y. Y. Liu, H. X. Bai, W. Li &amp; J. Z. Zhan</i>  | 241 |
| Recent Advances on UHV Technique (Problems Related to Utilization of Aluminium Alloys)<br><i>S. Komiya</i>                                       | 254 |
| Research of Gas Molecules Movement Rules in an Extrahigh Vacuum (XHV)<br><i>D. A. Da</i>   | 267 |
| Mass Discrimination Effect in Quadrupole Mass Spectrometers<br><i>B. Q. Yu</i>   | 276 |
| Direct Mass Spectrometric Diagnostics for a CO <sub>2</sub> Gas Laser<br><i>Y. Z. Wang &amp; J. S. Liu</i>                                       | 297 |
| New Partial Pressure Gauge for Helium and Deuterium Using Ion Backscattering Principle<br><i>K. Akaishi, A. Uritani, Y. Kubota &amp; Y. Hori</i> | 318 |
| TECHNICAL NOTE   | 333 |
| A New Microspot AES/SIMS for Monitoring of Semiconductor Surfaces<br><i>K. Hoshino</i>   | 335 |
| LIST OF PARTICIPANTS   | 361 |